

<b>Notice of References Cited</b>	Application/Control No. 10/630,643	Applicant(s)/Patent Under Reexamination YEW ET AL.	
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	C	US-6,225,207 B1	05-2001	Parikh, Suketu A.	438/622
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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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